

INTERNAL REPORTS IN
SIMULATION, OPTIMIZATION
AND CONTROL

No. SOC-142

YIELD ESTIMATION FOR EFFICIENT DESIGN CENTERING
ASSUMING ARBITRARY STATISTICAL DISTRIBUTIONS

H.L. Abdel-Malek and J.W. Bandler

December 1976

(Revised June 1977)

FACULTY OF ENGINEERING
McMASTER UNIVERSITY
HAMILTON, ONTARIO, CANADA



AVAILABILITY OF REPORTS

In addition to extensive publications by G-SOC members, a series of reports covering simulation, optimization and control topics is published by the group. Preprints or extended versions of papers, reprints of papers appearing in conference proceedings, fully documented computer program descriptions including listings, theses, notes and manuals appear as reports.

A free list of SOC reports including numbers, titles, authors, dates of publication, and indication of the inclusion of computer listings is available on request. To offset preparation, printing and distribution costs the charges as noted must be made*.

Any number of these reports may be ordered**. Cheques should be made out in U.S. or Canadian Dollars and made payable to McMaster University. Requests must be addressed to:

Dr. J.W. Bandler
Coordinator, G-SOC
Faculty of Engineering
McMaster University
Hamilton, Canada L8S 4L7

Reports will not normally be sent out until payment is received.

Some reports may be temporarily restricted for internal use only. Some may be revised or ultimately superceded. Availability, descriptions or charges are subject to change without notice.

Typical of the 173 reports published up to June 1977 are:

SOC-29	DISOPT - A General Program for Continuous and Discrete Nonlinear Programming Problems***	Mar. 1974	80 pp.	\$30
SOC-43	Convergence Acceleration in the Numerical Solution of Field Problems	Jun. 1974	324 pp.	\$30
SOC-61	Canonical Forms for Linear Multi-variable Systems	Oct. 1974	29 pp.	\$5
SOC-82	Optimal Choice of the Sampling Interval for Discrete Process Control	Mar. 1975	41 pp.	\$5
SOC-113	Notes on Numerical Methods of Optimization with Applications in Optimal Design***	Nov. 1975	396 pp.	\$150
SOC-151	FLOPT4-A Program for Least pth Optimization with Extrapolation to Minimax Solutions***	Jan. 1977	97 pp.	\$60

* Subscriptions and discounts are available.

** Special reduced rates will be quoted for multiple copies.

*** Include FORTRAN listings.

YIELD ESTIMATION FOR EFFICIENT DESIGN CENTERING ASSUMING
ARBITRARY STATISTICAL DISTRIBUTIONS

H.L. Abdel-Malek, Student Member, IEEE,
and J.W. Bandler, Senior Member, IEEE

Abstract

Based upon a uniform distribution inside an orthocell in the tolerated parameter space, it is shown how production yield and yield sensitivities can be evaluated for arbitrary statistical distributions. Formulas for yield and yield sensitivities in the case of a uniform distribution of outcomes between the tolerance extremes are given. A general formula for the yield, which is applicable to any arbitrary statistical distribution, is presented. An illustrative example for verifying the formulas is given. Karafin's bandpass filter has been used for applying the yield formula for a number of different statistical distributions. Uniformly distributed parameters between tolerance extremes, uniformly distributed parameters with accurate components removed and normally distributed parameters were considered. Comparisons with Monte Carlo analysis were made to contrast efficiency.

This work was supported by the National Research Council of Canada under Grant A7239. This paper was presented at the Conference on Computer-aided Design of Electronic and Microwave Circuits and Systems, Hull, England, July 12-14, 1977.

The authors are with the Group on Simulation, Optimization and Control and Department of Electrical Engineering, McMaster University, Hamilton, Canada, L8S 4L7.

I. INTRODUCTION

Design centering and enlarging parameter tolerances, particularly for mass-produced designs such as integrated circuits, is a requirement for cost reduction. It is this aim which emphasizes the problem of yield estimation and makes it an integral part of the design process.

The yield problem has usually been treated through the Monte Carlo method of analysis. Elias [1] presented an approach which applies the Monte Carlo analysis directly to the nonlinear constraints. In an effort to reduce computational time Director and Hachtel [2] suggested applying the Monte Carlo method in conjunction with a polytope describing the constraint region. This polytope (a simplex being a special case [3]) might be defined by quite a large number of hyperplanes. For example, for a space of k dimensions, as described by the algorithm, this number may initially be 2^k . Scott and Walker [4] suggested an efficient technique using Monte Carlo analysis with space regionalization. However, the number of required analyses increases exponentially with the number of variables in order to get the response at the center of each region. Regionalization was later used by Leung and Spence [5] exploiting the technique of systematic exploration. This technique is only applicable to linear circuits.

Karafin [6] used a different approach. The yield was estimated according to truncated Taylor series approximations for the constraints. In the approach presented here we assume a reasonable nominal point and reasonable linear approximations to the constraints. These will usually be available if a centering or a worst-case tolerance assignment problem is solved first. The assumption of a reasonable nominal point was also required by Karafin [6].

The approach is based upon partitioning the region under consideration into a collection of orthotopic cells (orthocells). A weight is assigned to

each orthocell and a uniform distribution is assumed inside it. The weights are obtained from tabulated values for known distributions or obtained according to sampling the components used. The freedom in choosing the sizes of the orthocells allows the use of previous information about the problem. A formula for the yield is derived according to these assumptions and it is applicable to any statistical distribution, whether we have independent parameters or correlated parameters with discrete or continuous tolerances.

An illustrative example was used to verify the yield and the yield sensitivity formulas for the uniform case. A comparison with the Monte Carlo analysis method as applied to Karafin's bandpass filter [6] is given for the following statistical distributions:

- (a) A uniform distribution of outcomes between tolerance extremes using different values for the tolerances.
- (b) A uniform distribution of outcomes between tolerance extremes, but with more accurate components selected out.
- (c) Parameters with normal distributions for different values of the standard deviation.

Since the uniform distribution is basic to the presentation, we solve the problem of a uniform distribution first and generalize it for any distribution later.

II. YIELD WITH A UNIFORM DISTRIBUTION

The yield is simply defined by

$$Y \triangleq N/M, \quad (1)$$

where N is the number of outcomes which satisfy the specifications and M is the total number of outcomes.

Define the tolerance region R_ϵ by

$$R_{\epsilon} \triangleq \left\{ \underset{\sim}{\phi} \mid \phi_i^0 - \epsilon_i \leq \phi_i \leq \phi_i^0 + \epsilon_i, i = 1, 2, \dots, k \right\}, \quad (2)$$

where k is the number of designable parameters, $\underset{\sim}{\phi}^0$ is the nominal parameter vector and $\underset{\sim}{\epsilon}$ is the vector of absolute tolerances of the corresponding parameters.

Now, define the function $V(R)$ as the hypervolume of the set R . Thus, for the case of independent parameters and assuming a uniform distribution of outcomes between the tolerance extremes, (1) reduces to

$$Y = \frac{V(R_{\epsilon} \cap R_c)}{V(R_{\epsilon})}, \quad (3)$$

where

$$R_c \triangleq \left\{ \underset{\sim}{\phi} \mid g_{\ell}(\underset{\sim}{\phi}) \geq 0, \ell = 1, 2, \dots, m \right\} \quad (4)$$

is the constraint region defined by m linearized constraints

$$g_{\ell}(\underset{\sim}{\phi}) = \underset{\sim}{\phi}^T \underset{\sim}{q}^{\ell} - c^{\ell}, \ell = 1, 2, \dots, m. \quad (5)$$

Assuming no overlapping of nonfeasible regions defined by different constraints inside the orthotope R_{ϵ} , i.e.,

$$R_i \cap_{i \neq j} R_j = \emptyset, \quad (6)$$

where

$$R_{\ell} \triangleq \left\{ \underset{\sim}{\phi} \mid g_{\ell}(\underset{\sim}{\phi}) < 0 \right\} \cap R_{\epsilon}, \quad (7)$$

the yield can be expressed as

$$Y = 1 - \frac{\sum_{\ell=1}^m V(R_{\ell})}{V(R_{\epsilon})}. \quad (8)$$

Define the set of all vertices of the orthotope R_{ϵ} by [7]

$$R_V \triangleq \left\{ \underset{\sim}{\phi} \mid \underset{\sim}{\phi} = \underset{\sim}{\phi}^0 + E \underset{\sim}{\mu}, \mu_i \in \{-1, 1\}, i = 1, 2, \dots, k \right\}, \quad (9)$$

where E is a $k \times k$ diagonal matrix with ϵ_i , $i = 1, 2, \dots, k$ along the diagonal and using the following vertex enumeration scheme:

$$r = 1 + \sum_{i=1}^k \frac{\mu_i^r + 1}{2} 2^{i-1} \quad (10)$$

Corresponding to each constraint $g_\ell(\phi) \geq 0$, let us define a reference vertex

$$\phi^r = \phi^0 + \sum \mu^r \quad (11)$$

where

$$\mu_i^r = - \text{sign} (q_i^\ell) , i = 1, 2, \dots, k \quad (12)$$

If $g_\ell(\phi^r) \geq 0$, then $V(R_\ell) = 0$. Otherwise we find the distance between the intersection of the hyperplane $g_\ell(\phi) = 0$ and the reference vertex ϕ^r along an edge of R_ℓ in the i th direction given by

$$\begin{aligned} \alpha_i^\ell &= \mu_i^r g_\ell(\phi^r) / q_i^\ell \\ &= \mu_i^r \left\{ \phi_i^0 + \mu_i^r \varepsilon_i - \frac{1}{q_i^\ell} \left[c^\ell - \sum_{\substack{j=1 \\ j \neq i}}^k q_j^\ell (\phi_j^0 + \mu_j^r \varepsilon_j) \right] \right\} , i=1,2,\dots,k. \end{aligned} \quad (13)$$

In order to derive an expression for $V^\ell = V(R_\ell)$, consider the two-dimensional examples shown in Fig. 1. The nonfeasible area in Fig. 1(a) is given by

$$\begin{aligned} V &= \Delta \phi^r ab - \Delta \phi^4 ac - \Delta \phi^1 bd \\ &= \frac{1}{2} \alpha_1 \alpha_2 - \frac{1}{2} \left[\alpha_1 \left(1 - \frac{2\varepsilon_1}{\alpha_1} \right) \right] \left[\alpha_2 \left(1 - \frac{2\varepsilon_1}{\alpha_1} \right) \right] \\ &\quad - \frac{1}{2} \left[\alpha_1 \left(1 - \frac{2\varepsilon_2}{\alpha_2} \right) \right] \left[\alpha_2 \left(1 - \frac{2\varepsilon_2}{\alpha_2} \right) \right] \\ &= \frac{1}{2} \alpha_1 \alpha_2 \left[1 - \left(1 - \frac{2\varepsilon_1}{\alpha_1} \right)^2 - \left(1 - \frac{2\varepsilon_2}{\alpha_2} \right)^2 \right] . \end{aligned}$$

Also, in Fig. 1(b), the nonfeasible area is given by

$$V = \Delta \phi^r ab - \Delta \phi^4 ac - \Delta \phi^1 bd + \Delta \phi^2 cd$$

$$= \frac{1}{2} \alpha_1 \alpha_2 \left[1 - \left(1 - \frac{2\epsilon_1}{\alpha_1} \right)^2 - \left(1 - \frac{2\epsilon_2}{\alpha_2} \right)^2 + \left(1 - \frac{2\epsilon_1}{\alpha_1} - \frac{2\epsilon_2}{\alpha_2} \right)^2 \right] .$$

A three-dimensional example is shown in Fig. 2. In that example the linear constraint cuts the orthotope at the polygon a b c d e and the volume is given by

$$V = \frac{1}{6} \alpha_1 \alpha_2 \alpha_3 - \frac{1}{6} \alpha_1 \alpha_2 \alpha_3 \left(1 - \frac{2\epsilon_1}{\alpha_1} \right)^3 - \frac{1}{6} \alpha_1 \alpha_2 \alpha_3 \left(1 - \frac{2\epsilon_2}{\alpha_2} \right)^3 - \frac{1}{6} \alpha_1 \alpha_2 \alpha_3 \left(1 - \frac{2\epsilon_3}{\alpha_3} \right)^3 + \frac{1}{6} \alpha_1 \alpha_2 \alpha_3 \left(1 - \frac{2\epsilon_1}{\alpha_1} - \frac{2\epsilon_2}{\alpha_2} \right)^3 .$$

Hence, the general formula can be written as

$$V(R_\ell) = \left\{ \frac{1}{k!} \prod_{j=1}^k \alpha_j^\ell \right\} \left\{ \sum_{s \in S_\ell} (-1)^{v^s} (\delta_\ell^s)^k \right\} , \quad (14)$$

where

$$\delta_\ell^s = 1 - \sum_{j=1}^k \frac{\epsilon_j}{\alpha_j} \left| \mu_j^s - \mu_j^r \right| , \quad (15)$$

$$S_\ell \triangleq \left\{ s \mid g_\ell(\phi^s) < 0, \phi^s = \phi^0 + \sum \mu^s \right\} , \quad (16)$$

$$v^s = \sum_{i=1}^k \left| \mu_i^s - \mu_i^r \right| / 2 . \quad (17)$$

An illustration of (14) for the case of $k = 3$ is shown in Fig. 2. Since

$$V(R_\epsilon) = 2^k \prod_{j=1}^k \epsilon_j , \quad (18)$$

the yield sensitivities can be expressed as

$$\frac{\partial Y}{\partial \phi_i} = - \sum_{\ell=1}^m \frac{\partial V_\ell}{\partial \phi_i} / V(R_\epsilon) , \quad (19)$$

$$\frac{\partial Y}{\partial \epsilon_i} = \left(\frac{1}{\epsilon_i} \sum_{\ell=1}^m V^\ell - \sum_{\ell=1}^m \frac{\partial V^\ell}{\partial \epsilon_i} \right) / V(R_\epsilon) \quad (20)$$

We take

$$\frac{\partial V^\ell}{\partial \phi_i} = \frac{\partial V^\ell}{\partial \epsilon_i} = 0 \quad \text{if } g_\ell(\phi^r) \geq 0 \quad ,$$

otherwise

$$\begin{aligned} \frac{\partial V^\ell}{\partial \phi_i} = & \left\{ \frac{q_i^\ell}{k!} \sum_{p=1}^k \left[\frac{\mu_p^r}{q_p^\ell} \prod_{\substack{j=1 \\ j \neq p}}^k \alpha_j^\ell \right] \right\} A \\ & + B \left\{ k q_i^\ell \sum_{s \in S_\ell} (-1)^{v^s} (\delta_\ell^s)^{k-1} \left(\sum_{j=1}^k \frac{\mu_j^r}{q_j^\ell} \frac{\epsilon_j}{(\alpha_j^\ell)^2} \left| \mu_j^s - \mu_j^r \right| \right) \right\} \quad , \quad (21) \end{aligned}$$

$$\frac{\partial V^\ell}{\partial \epsilon_i} = \mu_i^r \frac{\partial V^\ell}{\partial \phi_i} - B \left\{ \frac{k}{\alpha_i^\ell} \sum_{s \in S_\ell} \left| \mu_i^s - \mu_i^r \right| (-1)^{v^s} (\delta_\ell^s)^{k-1} \right\} \quad , \quad (22)$$

where

$$A = \sum_{s \in S_\ell} (-1)^{v^s} (\delta_\ell^s)^k \quad , \quad (23)$$

$$B = \frac{1}{k!} \prod_{j=1}^k \alpha_j^\ell \quad . \quad (24)$$

It is to be noted that the yield sensitivities are discontinuous whenever a vertex ϕ^s satisfies the equation $g_\ell(\phi^s) = 0$ for any $\ell = 1, 2, \dots, m$. Also for the case of having $\alpha_j \rightarrow \infty$ there exists a limit for the hypervolume formula and its sensitivities.

For an alternative way of calculating $V(R_\ell)$ we define a complementary vertex

$$\underline{\phi}^{\bar{r}} = \underline{\phi}^0 + \underline{E} \underline{\mu}^{\bar{r}} \quad , \quad (25)$$

where

$$\underline{\mu}_i^{\bar{r}} = - \underline{\mu}_i^r = \text{sign} (q_i^{\bar{r}}) \quad , \quad i = 1, 2, \dots, k. \quad (26)$$

If $g_\ell(\underline{\phi}^{\bar{r}}) \leq 0$, then $V(R_\ell) = V(R_\varepsilon)$. Otherwise we find the distance between the intersection of the hyperplane $g_\ell(\underline{\phi}) = 0$ and the complementary vertex $\underline{\phi}^{\bar{r}}$ along an edge of R_ε in the i th direction given by

$$\underline{\alpha}_i^{\bar{r}} = \underline{\mu}_i^{\bar{r}} g_\ell(\underline{\phi}^{\bar{r}}) / q_i^{\bar{r}} \quad , \quad i = 1, 2, \dots, k. \quad (27)$$

Hence we find the following equations:

$$V^\ell = V(R_\ell) = 2^k \prod_{j=1}^k \varepsilon_j - \left\{ \frac{1}{k!} \prod_{j=1}^k \underline{\alpha}_j^{\bar{r}} \right\} \left\{ \sum_{s \in \bar{S}_\ell} (-1)^{\bar{v}^s} (\bar{\delta}_\ell^s)^k \right\} \quad , \quad (28)$$

where

$$\bar{\delta}_\ell^s = 1 - \sum_{j=1}^k \frac{\varepsilon_j}{\underline{\alpha}_j^{\bar{r}}} \left| \mu_j^s - \underline{\mu}_j^{\bar{r}} \right| \quad , \quad (29)$$

$$\bar{S}_\ell \triangleq \left\{ s \mid g_\ell(\underline{\phi}^s) > 0, \underline{\phi}^s = \underline{\phi}^0 + \underline{E} \underline{\mu}^s \right\} \quad , \quad (30)$$

$$\bar{v}^s = \sum_{i=1}^k \left| \mu_i^s - \underline{\mu}_i^{\bar{r}} \right| / 2 \quad . \quad (31)$$

Equations (19) and (20) remain as before.

We take

$$\frac{\partial V^\ell}{\partial \phi_i^0} = 0 \quad \text{and} \quad \frac{\partial V^\ell}{\partial \varepsilon_i} = 2^k \prod_{\substack{j=1 \\ j \neq i}}^k \varepsilon_j \quad \text{if} \quad g_\ell(\underline{\phi}^{\bar{r}}) \leq 0 \quad ,$$

otherwise

$$\frac{\partial V^{\ell}}{\partial \phi_i} = - \left\{ \frac{q_i^{\ell}}{k!} \sum_{p=1}^k \left[\frac{\mu_p^{\bar{r}}}{q_p^{\ell}} \prod_{\substack{j=1 \\ j \neq p}}^k \frac{\alpha_j^{\ell}}{\alpha_j} \right] \right\} \bar{A} \\ - \bar{B} \left\{ k q_i^{\ell} \sum_{s \in \bar{S}_{\ell}} (-1)^{\bar{v}^s} (\bar{\delta}_{\ell}^s)^{k-1} \left(\sum_{j=1}^k \frac{\mu_j^{\bar{r}}}{q_j^{\ell}} \frac{\epsilon_j}{(\alpha_j^{\ell})^2} \left| \mu_j^s - \mu_j^{\bar{r}} \right| \right) \right\}, \quad (32)$$

$$\frac{\partial V^{\ell}}{\partial \epsilon_i} = 2^k \prod_{\substack{j=1 \\ j \neq i}}^k \epsilon_j + \mu_i^{\bar{r}} \frac{\partial V^{\ell}}{\partial \phi_i} + \bar{B} \left\{ \frac{k}{\alpha_i^{\ell}} \sum_{s \in \bar{S}_{\ell}} \left| \mu_i^s - \mu_i^{\bar{r}} \right| (-1)^{\bar{v}^s} (\bar{\delta}_{\ell}^s)^{k-1} \right\}, \quad (33)$$

where

$$\bar{A} = \sum_{s \in \bar{S}_{\ell}} (-1)^{\bar{v}^s} (\bar{\delta}_{\ell}^s)^k, \quad (34)$$

$$\bar{B} = \frac{1}{k!} \prod_{j=1}^k \frac{\alpha_j^{\ell}}{\alpha_j}. \quad (35)$$

In order to obtain the hypervolume and its sensitivities efficiently we use the following criteria:

- i) If $g_{\ell}(\phi_{\sim}^{\bar{r}}) \geq 0$, use reference vertex approach.
- ii) If $g_{\ell}(\phi_{\sim}^{\bar{r}}) \leq 0$, use complementary vertex approach.
- iii) If $g_{\ell}(\phi_{\sim}^{\bar{r}}) < 0$ and $g_{\ell}(\phi_{\sim}^{\bar{r}}) > 0$, then
 - if $|g_{\ell}(\phi_{\sim}^{\bar{r}})| \leq |g_{\ell}(\phi_{\sim}^{\bar{r}})|$, use reference vertex approach,
 - if $|g_{\ell}(\phi_{\sim}^{\bar{r}})| > |g_{\ell}(\phi_{\sim}^{\bar{r}})|$, use complementary vertex approach.

The cases i) and ii) are clear since the hypervolume will be either completely feasible or completely nonfeasible, respectively. Case iii) follows from the theorem in the Appendix.

Example 1

Consider the following four-dimensional example, with a linear constraint

$$g(\phi) = \frac{\phi_1}{24} + \frac{\phi_2}{15} + \frac{\phi_3}{60} + \frac{\phi_4}{240} - 1 \geq 0 ,$$

and where

$$\underset{\sim}{\phi}^0 = \begin{bmatrix} 9 \\ 7 \\ 9 \\ 26 \end{bmatrix} , \quad \underset{\sim}{\epsilon} = \begin{bmatrix} 5 \\ 2 \\ 4 \\ 6 \end{bmatrix} .$$

Hence,

$$\underset{\sim}{\phi}^r = \begin{bmatrix} 9 \\ 7 \\ 9 \\ 26 \end{bmatrix} + \begin{bmatrix} 5 & 0 & 0 & 0 \\ 0 & 2 & 0 & 0 \\ 0 & 0 & 4 & 0 \\ 0 & 0 & 0 & 6 \end{bmatrix} \begin{bmatrix} -1 \\ -1 \\ -1 \\ -1 \end{bmatrix} = \begin{bmatrix} 4 \\ 5 \\ 5 \\ 20 \end{bmatrix}$$

and

$$\begin{aligned} V &= \left[\frac{1}{4!} 8 \times 5 \times 20 \times 80 \right] \left[1 - \left(1 - \frac{4}{5} \right)^4 - \left(1 - \frac{8}{20} \right)^4 - \left(1 - \frac{12}{80} \right)^4 \right. \\ &\quad \left. + \left(1 - \frac{4}{5} - \frac{12}{80} \right)^4 + \left(1 - \frac{8}{20} - \frac{12}{80} \right)^4 \right] \\ &= 1034.15 . \end{aligned}$$

Table I shows the nonfeasible vertices. A check for the analytical formulas for the gradients and the numerical gradients obtained by central differences is shown in Table II.

The alternative approach will lead to

$$\underset{\sim}{\phi}^r = \begin{bmatrix} 9 \\ 7 \\ 9 \\ 26 \end{bmatrix} + \begin{bmatrix} 5 & 0 & 0 & 0 \\ 0 & 2 & 0 & 0 \\ 0 & 0 & 4 & 0 \\ 0 & 0 & 0 & 6 \end{bmatrix} \begin{bmatrix} 1 \\ 1 \\ 1 \\ 1 \end{bmatrix} = \begin{bmatrix} 14 \\ 9 \\ 13 \\ 32 \end{bmatrix}$$

and

$$\begin{aligned}
 V &= 2^4 \times 5 \times 2 \times 4 \times 6 - \left[\frac{1}{4!} (8 \times 1.6) (5 \times 1.6) (20 \times 1.6) (80 \times 1.6) \right] \\
 &\cdot \left[1 - \left(1 - \frac{10}{8 \times 1.6} \right)^4 - \left(1 - \frac{4}{5 \times 1.6} \right)^4 - \left(1 - \frac{8}{20 \times 1.6} \right)^4 + \left(1 - \frac{4}{5 \times 1.6} - \frac{8}{20 \times 1.6} \right)^4 \right. \\
 &\quad - \left(1 - \frac{12}{80 \times 1.6} \right)^4 + \left(1 - \frac{10}{8 \times 1.6} - \frac{12}{80 \times 1.6} \right)^4 + \left(1 - \frac{4}{5 \times 1.6} - \frac{12}{80 \times 1.6} \right)^4 \\
 &\quad \left. + \left(1 - \frac{8}{20 \times 1.6} - \frac{12}{80 \times 1.6} \right)^4 - \left(1 - \frac{4}{5 \times 1.6} - \frac{8}{20 \times 1.6} - \frac{12}{80 \times 1.6} \right)^4 \right] \\
 &= 3840 - 2805.85 = 1034.15 \quad .
 \end{aligned}$$

III. YIELD WITH STATISTICAL DISTRIBUTIONS

The probability distribution function (PDF) might extend as far as $(-\infty, \infty)$, however, for all practical cases we consider a tolerance region R_ϵ such that

$$\int_{R_\epsilon} F(\phi) \, d\phi_1 \, d\phi_2 \, \dots \, d\phi_k \approx 1 \quad , \quad (36)$$

where $F(\phi)$ is the PDF.

The orthotope R_ϵ is now partitioned into a set of orthocells $R(i_1, i_2, \dots, i_k)$ as in Fig. 3, where $i_j = 1, 2, \dots, n_j$, n_j is the number of intervals in the j th direction and $j = 1, 2, \dots, k$. A weighting factor $W(i_1, i_2, \dots, i_k)$ is assigned to each orthocell and is given by

$$W(i_1, i_2, \dots, i_k) = w(i_1, i_2, \dots, i_k) / V(R(i_1, i_2, \dots, i_k)) \quad , \quad (37)$$

where

$$w(i_1, i_2, \dots, i_k) = \int_{R(i_1, i_2, \dots, i_k)} F(\phi) \, dv \quad , \quad (38)$$

$$V(R(i_1, i_2, \dots, i_k)) = \int_{R(i_1, i_2, \dots, i_k)} dv = \prod_{j=1}^k \epsilon_{j, i_j} \quad , \quad (39)$$

$$dv = d\phi_1 d\phi_2 \dots d\phi_k \quad (40)$$

and $\epsilon_{1, i_1}, \epsilon_{2, i_2}, \dots, \epsilon_{k, i_k}$ are the dimensions of the orthocell.

In principle, the problem of finding the yield is now reduced to finding the contribution to the yield given by any of these orthocells. However, it will be a tedious job to consider $\prod_{j=1}^k n_j$ orthocells. By exploiting the way (14) is constructed, a formula for the weighted nonfeasible hypervolume with respect to the ℓ th constraint is constructed and is given by

$$V^\ell = \left[\frac{1}{k!} \prod_{j=1}^k \alpha_j^\ell \right] \left[\sum_{i_1=1}^{n_1+1} \sum_{i_2=1}^{n_2+1} \dots \sum_{i_k=1}^{n_k+1} \Delta W(i_1, i_2, \dots, i_k) (\delta_\ell(i_1, i_2, \dots, i_k))^k \right] \quad , \quad (41)$$

where, for indexing with respect to ϕ^r (see Fig. 3), α_j^ℓ = the distance from the reference vertex to the point of intersection in the j th direction,

$$\delta_\ell(i_1, i_2, \dots, i_k) = \max \left[0, \left[1 - \sum_{j=1}^k \frac{1}{\alpha_j^\ell} \sum_{p=1}^{i_j} \epsilon_{j, p-1} \right] \right] \quad , \quad (42)$$

$$\epsilon_{j, 0} = 0 \quad , \quad j = 1, 2, \dots, k \quad (43)$$

$$\begin{aligned} \Delta W(i_1, i_2, \dots, i_k) &= W(i_1, i_2, \dots, i_k) - \sum_{j=1}^k W(i_1, i_2, \dots, i_{j-1}, i_j-1, i_{j+1}, \dots, i_k) \\ &\quad + \sum_{j=1}^{k-1} \sum_{p=j+1}^k W(i_1, i_2, \dots, i_{j-1}, \dots, i_p-1, \dots, i_k) - \dots \\ &\quad + (-1)^k W(i_1-1, i_2-1, \dots, i_k-1) \end{aligned} \quad (44)$$

$$W(i_1, i_2, \dots, i_k) = 0 \quad \text{if } i_j = 0 \quad \text{or } i_j = n_j+1 \quad \text{for any } j. \quad (45)$$

For the case of independent parameters (41) can be written as

$$V^\ell = \left[\frac{1}{k!} \prod_{j=1}^k \alpha_j^\ell \right] \left[\sum_{i_1=1}^{n_1+1} \Delta W_1(i_1) \sum_{i_2=1}^{n_2+1} \Delta W_2(i_2) \dots \sum_{i_k=1}^{n_k+1} \Delta W_k(i_k) (\delta_\ell(i_1, i_2, \dots, i_k))^k \right] \quad (46)$$

where

$$\Delta W_j(i_j) = W_j(i_j) - W_j(i_j-1) \quad , \quad (47)$$

$$W_j(0) = W_j(n_j+1) = 0 \quad , \quad (48)$$

$$W_j(i_j) = \int_{R_j(i_j)} f_j(\phi_j) d\phi_j / \epsilon_{j,i_j} \quad , \quad i_j=1,2,\dots,n_j \quad , \quad (49)$$

$f_j(\phi_j)$ is the PDF of the j th parameter and $R_j(i_j)$ is the i th interval for that parameter. Table III illustrates the calculation of weighted hypervolume.

Again, assuming nonoverlapping, nonfeasible regions defined by different constraints inside the orthotope R_ϵ , the yield can be expressed as

$$Y = 1 - \sum_{\ell=1}^m V^\ell \quad . \quad (50)$$

In short, the method approximates the integration of the PDF over the feasible region. It allows freedom in discretizing the PDF which is an advantage particularly if a worst-case solution is already known.

Example 2

The bandpass filter [6, 8], shown in Fig. 4, was used for verification of the yield formula. The specifications are shown in Table IV. All inductors have the same Q at the nominal value given in [8] as the corresponding inductors in [6]. The results given in [8] as indicated by the authors violates the specifications at unconsidered frequency points. The adjoint network technique was used for evaluating the sensitivities and, hence, linearizing the constraints

at these frequency points. The linearization was done at the worst violating vertex, i.e., the vertex which gives the most negative value for that particular constraint. The yields obtained by the present approach and applying the Monte Carlo method with the nonlinear constraints for a uniform distribution are shown in Table V. Further, as the tolerances were increased more frequency points were considered. In order to avoid overlapping constraints, for each nonfeasible vertex the frequency point corresponding to the worst violated constraint is considered.

In addition, a uniform distribution of outcomes was considered but with the more accurate components removed. This gives $w_i(1) = w_i(3) = 0.5$ and $w_i(2) = 0$. The problem is equivalent to having 2^8 different orthotopes. The results are shown in Table VI.

Consider now the case of a normal distribution which has a probability distribution function [9]

$$F(\underline{\phi}) = \frac{1}{(2\pi)^{k/2}} \frac{1}{\sqrt{|\text{COV}|}} \exp \left[-\frac{1}{2} (\underline{\phi} - \underline{\phi}^0)^T (\text{COV})^{-1} (\underline{\phi} - \underline{\phi}^0) \right],$$

where

k is the number of parameters,

$\underline{\phi}^0$ is the mean value of the parameter vector $\underline{\phi}$,

COV is the covariance matrix.

In the case of no correlation, COV is a diagonal matrix with variances σ_i^2 , $i = 1, 2, \dots, k$, along the diagonal. Hence,

$$F(\underline{\phi}) = \frac{1}{(2\pi)^{k/2}} \frac{1}{\prod_{i=1}^k \sigma_i} \exp \left[-\sum_{i=1}^k \left(\frac{\phi_i - \phi_i^0}{\sigma_i} \right)^2 \right].$$

Using the described approach and dividing the interval $[\phi_i^0 - 2\sigma_i, \phi_i^0 + 2\sigma_i]$ for each parameter into three different subintervals the weights are obtained

in the following manner. Let [10]

$$I_1 = \frac{1}{\sqrt{2\pi} \sigma_i} \int_{-2\sigma_i}^{-2\sigma_i/3} \exp \left[- \left(\frac{\phi_i - \phi_i^0}{\sigma_i} \right)^2 \right] d\phi_i = 0.2298 \quad ,$$

$$I_2 = \frac{1}{\sqrt{2\pi} \sigma_i} \int_{-2\sigma_i/3}^{2\sigma_i/3} \exp \left[- \left(\frac{\phi_i - \phi_i^0}{\sigma_i} \right)^2 \right] d\phi_i = 0.4950 \quad ,$$

$$I_3 = \frac{1}{\sqrt{2\pi} \sigma_i} \int_{2\sigma_i/3}^{2\sigma_i} \exp \left[- \left(\frac{\phi_i - \phi_i^0}{\sigma_i} \right)^2 \right] d\phi_i = 0.2298 \quad .$$

Considering a probability of unity for finding ϕ_i in the interval $[\phi_i - 2\sigma_i, \phi_i + 2\sigma_i]$, the weights for each interval are given by (see Fig. 5)

$$w_1 = w_3 = 0.2298 / (I_1 + I_2 + I_3) \quad ,$$

$$w_2 = 0.4950 / (I_1 + I_2 + I_3) \quad .$$

The results are shown in Table VII for equal standard deviations for all of the eight parameters and for two values, namely, 5% and 6%. Table VIII shows the execution time if Monte Carlo analysis is applied to the linear constraints for the case of normally distributed parameters.

IV. CONCLUSIONS

It has been shown how yield may be estimated for arbitrary statistical distributions in an efficient way without recourse to the Monte Carlo method. Examples involving a number of distributions have been presented and the results contrasted with those given by the Monte Carlo method.

For the case of a uniform distribution between tolerance extremes yield sensitivity formulas have been derived with respect to nominal parameter values

and tolerances assuming independent variables. These can be useful in optimization [11,12]. Since the uniform distribution is basic to the subsequent consideration of arbitrary distributions, it is felt that the ideas on sensitivity could be carried through to effect design centering with respect to given distributions.

As usual in iterative schemes the choice of starting point may be important. In the present work it is recommended that a rough solution to a worst-case centering and tolerance assignment problem be used to provide and identify suitable active constraints. This allows only essential constraints to be considered and provides some justification for a worst-case solution even if less than 100% yield is subsequently contemplated [11,12].

APPENDIX

Theorem

If $g_{\ell}(\underline{\phi}^r) < 0$, $g_{\ell}(\underline{\phi}^{\bar{r}}) > 0$ and $|g_{\ell}(\underline{\phi}^r)| \leq |g_{\ell}(\underline{\phi}^{\bar{r}})|$, then
 Order $(S_{\ell}) \leq$ Order (\bar{S}_{ℓ}) .

Proof

In the case under consideration the order of a set is simply the number of its elements. Assume that $s \in S_{\ell}$, then

$$\begin{aligned} g_{\ell}(\underline{\phi}^s) &= g_{\ell}(\underline{\phi}^r) + (\underline{\phi}^s - \underline{\phi}^r)^T \nabla g_{\ell}(\underline{\phi}^r) < 0, \\ &= g_{\ell}(\underline{\phi}^r) + \sum_{i=1}^k \epsilon_i (\mu_i^s - \mu_i^r) q_i^{\ell} < 0, \end{aligned}$$

or

$$-g_{\ell}(\underline{\phi}^r) + \sum_{i=1}^k \epsilon_i (-\mu_i^s + \mu_i^r) q_i^{\ell} > 0.$$

But, since

$$-g_{\ell}(\underline{\phi}^r) \leq g_{\ell}(\underline{\phi}^{\bar{r}}) \quad \text{and} \quad \mu_i^{\bar{r}} = -\mu_i^r,$$

then

$$g_{\ell}(\phi_{\sim}^{\bar{r}}) + \sum_{i=1}^k \epsilon_i (-\mu_i^s - \mu_i^{\bar{r}}) q_i^{\ell} > 0,$$

i.e.,

$$g_{\ell}(\phi_{\sim}^{\bar{s}}) > 0,$$

where

$$\phi_{\sim}^{\bar{s}} = \phi_{\sim}^0 - \sum \mu_{\sim}^s.$$

Hence,

$$\bar{s} \in \bar{S}_{\ell}.$$

This means that for each vertex $s \in S_{\ell}$ there exists a vertex $\bar{s} \in \bar{S}_{\ell}$, thus

$$\text{Order}(S_{\ell}) \leq \text{Order}(\bar{S}_{\ell}).$$

REFERENCES

- [1] N.J. Elias, "New statistical methods for assigning device tolerances", Proc. 1975 IEEE Int. Symp. on Circuits and Systems (Newton, Mass., April 1975), pp. 329-332.
- [2] S.W. Director and G.D. Hachtel, "The simplicial approximation approach to design centering and tolerance assignment", Proc. 1976 IEEE Symp. on Circuits and Systems (Munich, April 1976), pp. 706-709.
- [3] H.S.M. Coxeter, Regular Polytopes (2nd. Ed.). New York: MacMillan, 1963, Chap. 7.
- [4] T.R. Scott and T.P. Walker, "Regionalization: a method for generating joint density estimates", IEEE Trans. Circuits and Systems, vol. CAS-23, April 1976, pp. 229-234.
- [5] K.H. Leung and R. Spence, "Idealized statistical models for low-cost linear circuit yield analysis", IEEE Trans. Circuits and Systems, vol. CAS-24, Feb. 1977, pp. 62-66.
- [6] B.J. Karafin, "The general component tolerance assignment problem in electrical networks", Ph.D. Thesis, Univ. of Pennsylvania, Philadelphia, Penn., 1974.

- [7] J.W. Bandler, "Optimization of design tolerances using nonlinear programming", J. Optimization Theory and Appl., vol. 14, July 1974, pp. 99-114.
- [8] J.W. Bandler and P.C. Liu, "Automated network design with optimal tolerances", IEEE Trans. Circuits and Systems, vol. CAS-21, March 1974, pp. 219-222.
- [9] M.F. Neuts, Probability. Boston, Mass.: Allyn and Bacon, 1973, pp. 189-192.
- [10] M. Abramowitz and I. Stegun, Handbook of Mathematical Functions. New York: Dover Publications, 1965, pp. 976-977.
- [11] J.W. Bandler and H.L. Abdel-Malek, "Optimal centering, tolerancing and yield determination using multidimensional approximations", Proc. 1977 IEEE Symp. on Circuits and Systems (Phoenix, April 1977), pp. 219-222.
- [12] J.W. Bandler and H.L. Abdel-Malek, "Optimal centering, tolerancing and yield determination using updated approximations and cuts", Faculty of Engineering, McMaster University, Hamilton, Canada, Report SOC-173, June 1977.

TABLE I
NONFEASIBLE VERTICES FOR EXAMPLE 1

Vertex	ϕ_1	ϕ_2	ϕ_3	ϕ_4	μ_1	μ_2	μ_3	μ_4	Nonfeasible vertices
1	4	5	5	20	-1	-1	-1	-1	X
2	14	5	5	20	1	-1	-1	-1	
3	4	9	5	20	-1	1	-1	-1	X
4	14	9	5	20	1	1	-1	-1	
5	4	5	13	20	-1	-1	1	-1	X
6	14	5	13	20	1	-1	1	-1	
7	4	9	13	20	-1	1	1	-1	
8	14	9	13	20	1	1	1	-1	
9	4	5	5	32	-1	-1	-1	1	X
10	14	5	5	32	1	-1	-1	1	
11	4	9	5	32	-1	1	-1	1	X
12	14	9	5	32	1	1	-1	1	
13	4	5	13	32	-1	-1	1	1	X
14	14	5	13	32	1	-1	1	1	
15	4	9	13	32	-1	1	1	1	
16	14	9	13	32	1	1	1	1	

TABLE II
HYPERVOLUME GRADIENT CHECK FOR EXAMPLE 1

Parameters	Analytical gradients	Numerical gradients
ϕ_1^0	-337.50	-337.50
ϕ_2^0	-540.00	-540.00
ϕ_3^0	-135.00	-135.00
ϕ_4^0	- 33.75	- 33.75
ϵ_1	337.50	337.50
ϵ_2	573.60	573.60
ϵ_3	268.20	268.20
ϵ_4	173.18	173.18

TABLE III

EXAMPLE OF CALCULATION OF WEIGHTED HYPERVOLUME BY THE GENERAL FORMULA

Orthocell dimensions	i_1	0	1	2	3	4	
	ϵ_{1,i_1}	0	3.0	3.0	2.0	-	
i_2	ϵ_{2,i_2}						
0	0	w, W	0	0	0	0	
1	2.0	w	0	18/100	12/100	3/10	0
		W	0	3/100	1/50	3/40	0
		ΔW	-	3/100	-1/100	11/200	-3/40
		δ	-	1	3/4	1/2	1/3
2	3.0	w	0	12/100	8/100	2/10	0
		W	0	1/75	2/225	1/30	0
		ΔW	-	-1/60	1/180	-11/360	1/24
		δ	-	1/3	1/12	0	0
3	-	w, W	0	0	0	0	0
		ΔW	-	-1/75	1/225	-11/450	1/30
		δ	-	0	0	0	0

Reference vertex ϕ^r given by $\mu_1^r = -1, \mu_2^r = 1$

Intersections of the linear constraint are $\alpha_1 = 12, \alpha_2 = 3$

Weighted volume $V = 1813/3600$

TABLE IV
SPECIFICATIONS FOR THE BANDPASS FILTER

Frequency range (Hz)	Relative insertion loss (dB)	Type
0 - 240	35	lower (stopband)
360 - 490	3	upper (passband)
700 - 1000	35	lower (stopband)

Reference frequency 420 Hz (fixed, therefore, ripples higher than 3 dB are to be expected in the passband)

Nominal values $L_1^0=3.0142$, $C_2^0=4.975 \times 10^{-8}$, $L_3^0=2.902$, $C_4^0=5.0729 \times 10^{-8}$,
 $L_5^0=0.82836$, $C_6^0=5.5531 \times 10^{-7}$, $L_7^0=0.30319$ and $C_8^0=1.6377 \times 10^{-7}$

TABLE V
 COMPARISON WITH THE MONTE CARLO ANALYSIS FOR UNIFORM
 DISTRIBUTION BETWEEN TOLERANCE EXTREMES

Tolerances (%)								Sample points (Hz)	Yield (%)		CDC Time (sec)	
ϵ_1/L_1^0	ϵ_2/C_2^0	ϵ_3/L_3^0	ϵ_4/C_4^0	ϵ_5/L_5^0	ϵ_6/C_6^0	ϵ_7/L_7^0	ϵ_8/C_8^0		Approx.	M.C.	Approx.*	M.C.**
6.99	6.52	6.97	6.55	4.36	5.69	6.80	5.25	188, 700, 876	100.00	99.75	0.67	24.0
7.00	7.00	7.00	7.00	5.00	6.00	7.00	6.00	188, 700, 876	100.00	99.65	0.66	24.2
8.00	8.00	8.00	8.00	6.00	7.00	8.00	7.00	{ 188, 700, 876 190, 240, 360, 480, 490, 700, 860	99.99	99.60	0.67	24.4
10.00	10.00	10.00	10.00	10.00	10.00	10.00	10.00		99.94	99.35	1.56	52.4
10.00	10.00	10.00	10.00	10.00	10.00	10.00	10.00	190, 240, 360, 480, 490, 700, 860	92.62	93.00	1.67	51.4

CDC time for selecting frequency points = 7.65 sec

* This time includes the linearization time

** 2000 points were used in Monte Carlo (M.C.) analyses with the nonlinear constraints

TABLE VI
COMPARISON WITH THE MONTE CARLO ANALYSIS FOR
ACCURATE COMPONENTS REMOVED

$\frac{\phi_i - \phi_i^0}{\phi_i^0}$ (%)	Yield (%)		CDC Time (sec)	
	Approx.	M.C.	Approx.	M.C.
[-10,-5], [5,10]	68.9	71.0	4.9	45.6

Frequency points used are 190, 240, 360, 480, 490, 700 and 860 Hz

TABLE VII
COMPARISON WITH MONTE CARLO ANALYSIS FOR
NORMALLY DISTRIBUTED COMPONENTS

$\frac{\sigma_i}{\phi_i}$ (%)	Yield (%)		CDC Time (sec)	
	Approx.	M.C.	Approx.	M.C.
5.0	96.5	95.1	4.9	69.2
6.0	88.4	87.0	7.4	68.0

TABLE VIII
EFFECT OF NUMBER OF MONTE CARLO ANALYSES ON THE YIELD
BASED UPON THE LINEARIZED CONSTRAINTS

$\frac{\sigma_i}{\phi_i}$ (%)	N.O.M.P.*	Yield (%)	CDC Time (sec)
5.0	2000	94.4	24.6
	500	94.2	7.0
	200	91.5	2.8
6.0	2000	86.6	24.3
	500	85.2	6.9
	200	84.0	2.8

* N.O.M.P. denotes the number of Monte Carlo points used

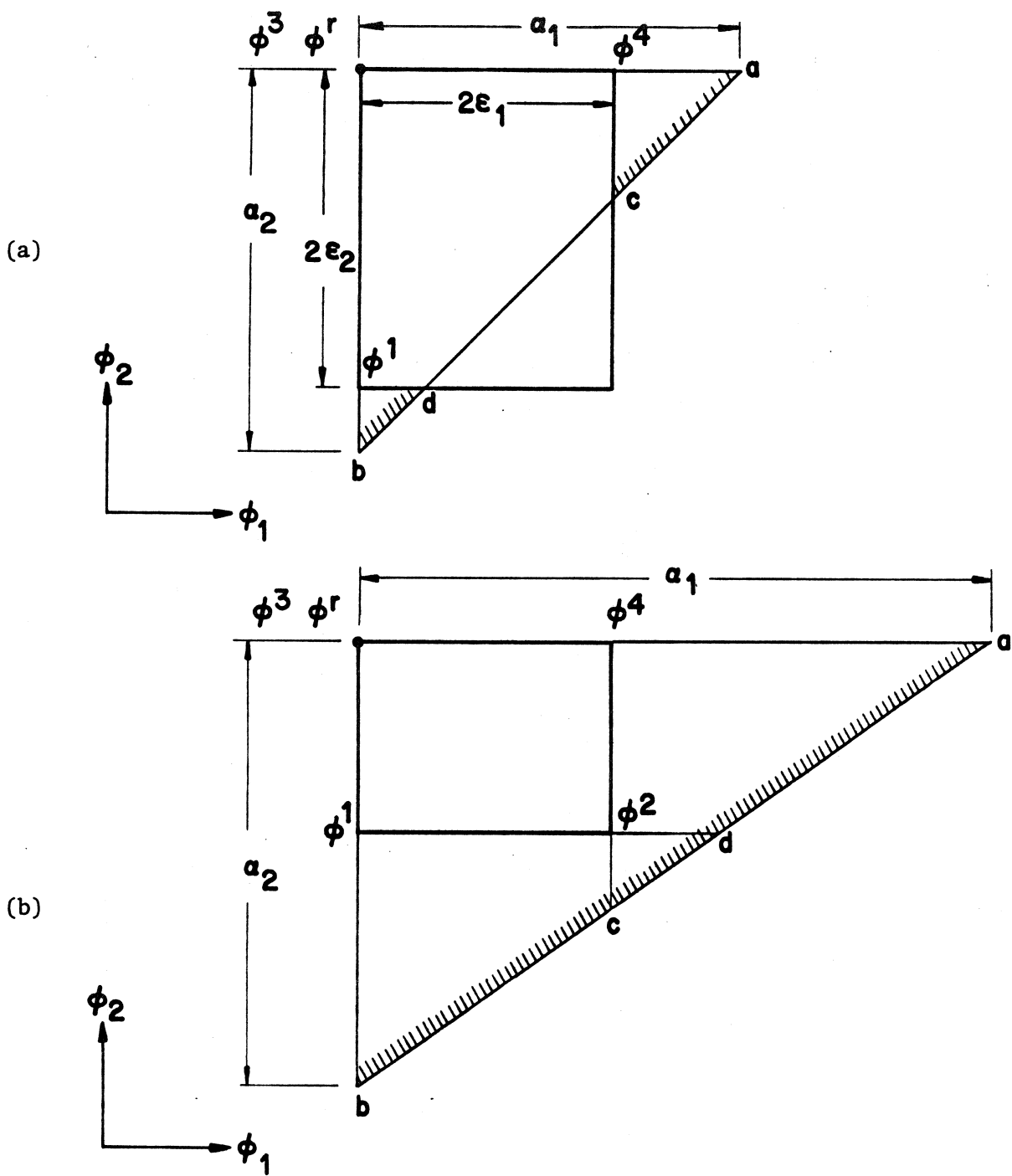


Fig. 1 Two-dimensional examples illustrating the calculation of the nonfeasible hypervolumes, (a) tolerance region partially feasible, (b) tolerance region nonfeasible.

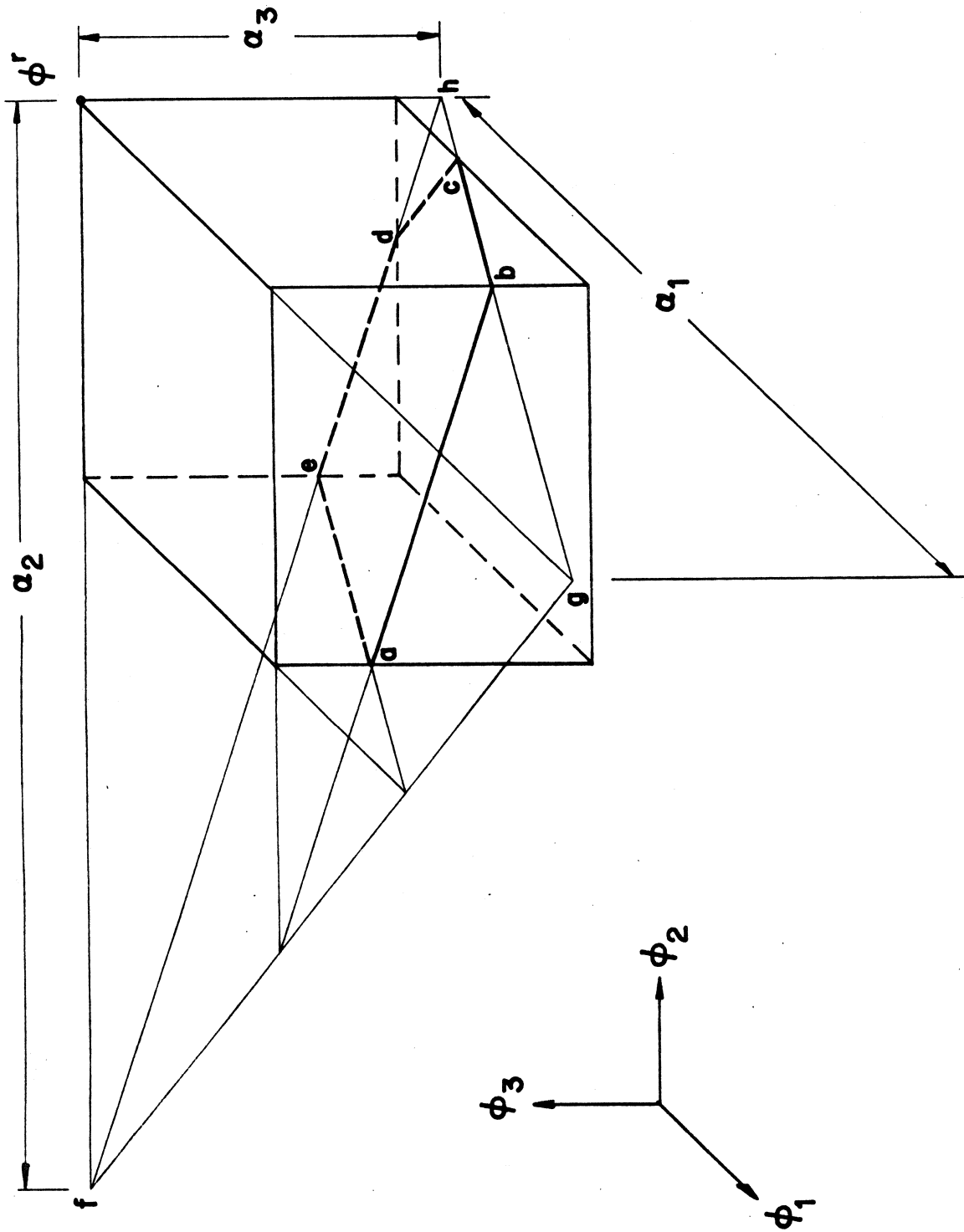


Fig. 2 Three-dimensional example illustrating the calculation of nonfeasible hypervolumes in the case of a partially feasible tolerance region.

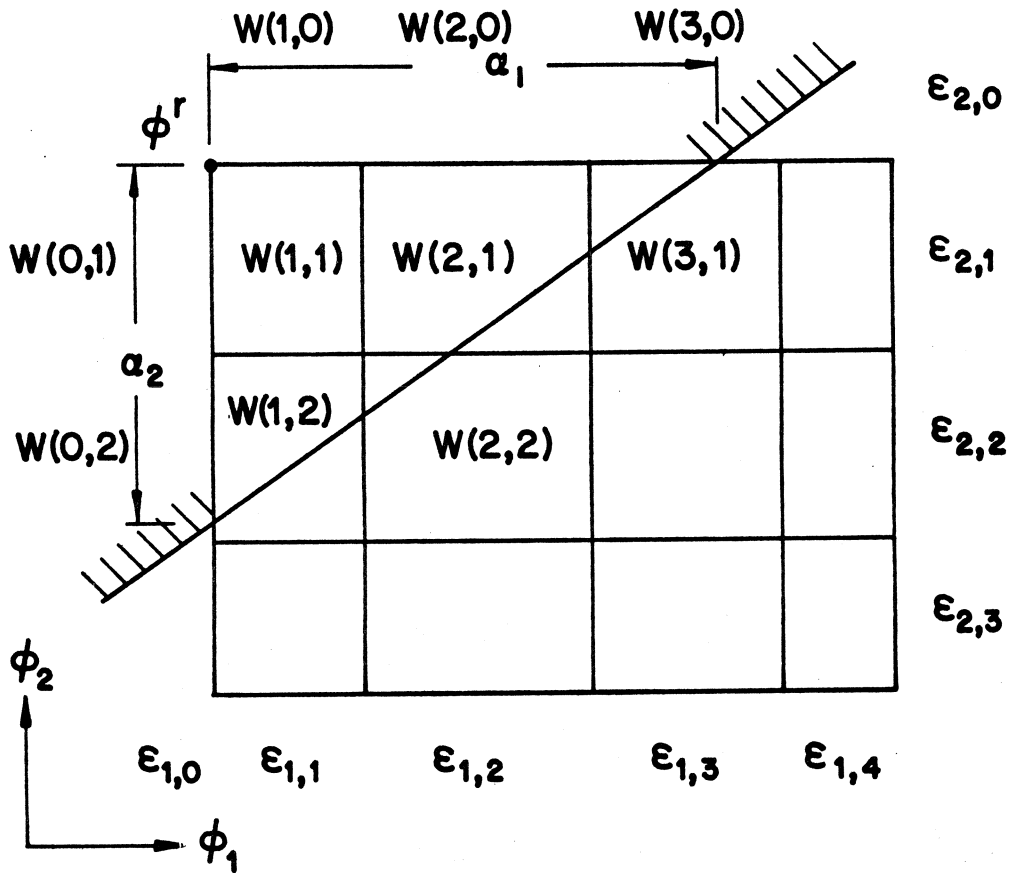


Fig. 3 Two-dimensional illustration of the partitioning of the tolerance region into cells indicating the dimensions and weighting of those cells relevant to the calculation of the weighted nonfeasible hypervolume.

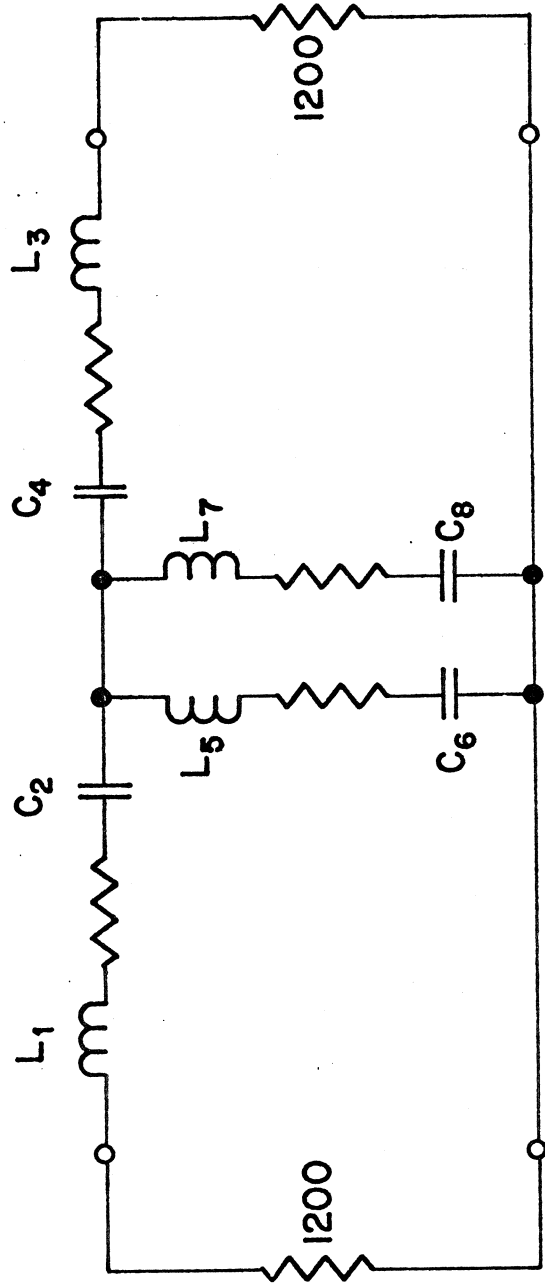


Fig. 4 Karafin's bandpass filter. The values of the resistances are related to nominal values of the corresponding inductances by the same ratio used by Karafin [6, p. 112].

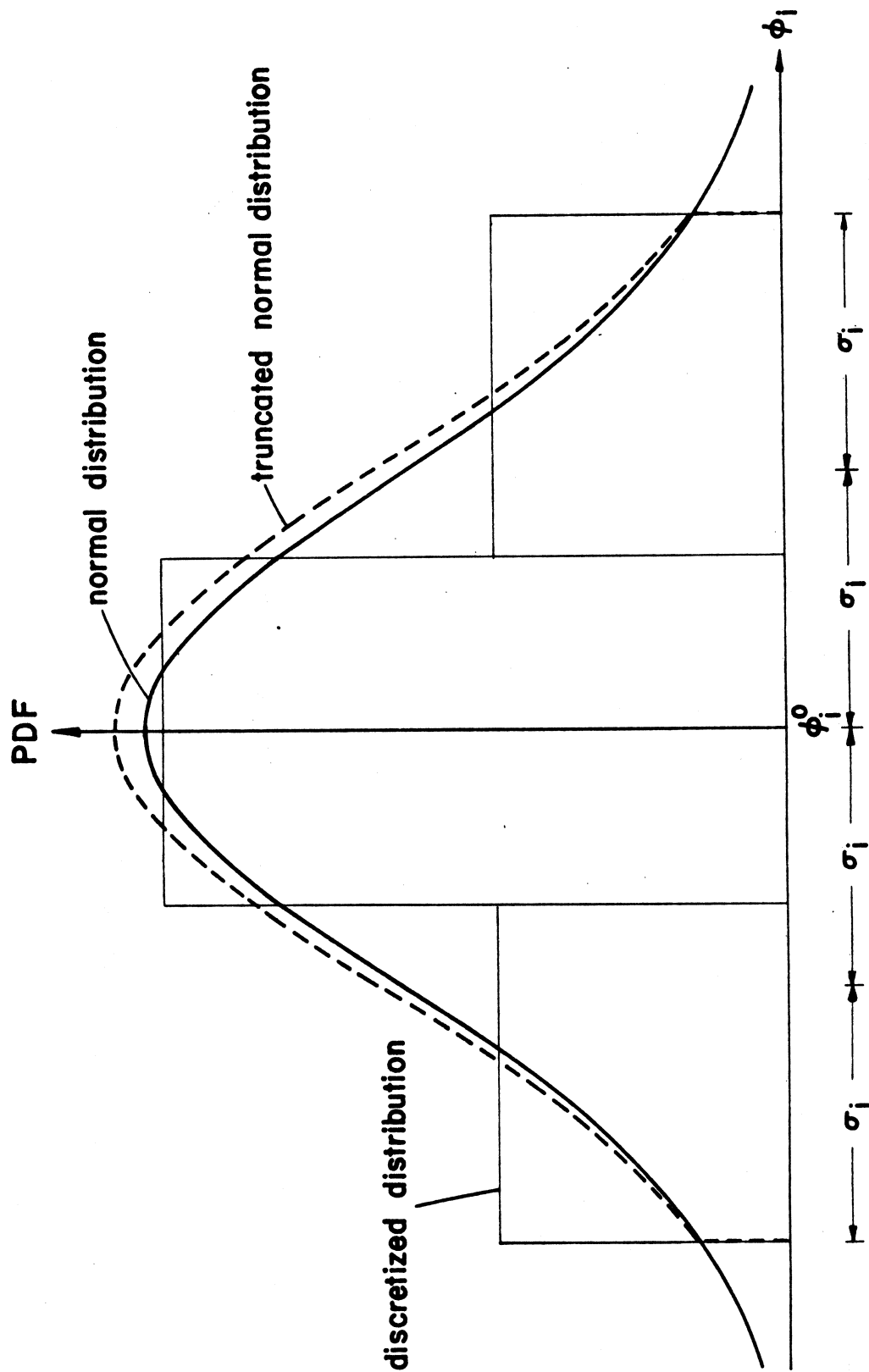


Fig. 5 Normal distribution, truncated normal distribution and discretized normal distribution.

SOC-142

YIELD ESTIMATION FOR EFFICIENT DESIGN CENTERING ASSUMING ARBITRARY
STATISTICAL DISTRIBUTIONS

H.L. Abdel-Malek and J.W. Bandler

December 1976, No. of Pages: 29

Revised: June 1977

Key Words: Design centering, yield estimation, statistical design,
Monte Carlo analysis

Abstract: Based upon a uniform distribution inside an orthocell in the toleranced parameter space, it is shown how production yield and yield sensitivities can be evaluated for arbitrary statistical distributions. Formulas for yield and yield sensitivities in the case of a uniform distribution of outcomes between the tolerance extremes are given. A general formula for the yield, which is applicable to any arbitrary statistical distribution, is presented. An illustrative example for verifying the formulas is given. Karafin's bandpass filter has been used for applying the yield formula for a number of different statistical distributions. Uniformly distributed parameters between tolerance extremes, uniformly distributed parameters with accurate components removed and normally distributed parameters were considered. Comparisons with Monte Carlo analysis were made to contrast efficiency.

Description: Presented at the Conference on Computer-aided Design of Electronic and Microwave Circuits and Systems (Hull, England, July 1977).

Related Work: As for SOC-1, in particular, SOC-132, SOC-173.

Price: \$ 5.00.

